

Search Notes

Application/Control No.

10/629,634

Examiner

TUAN A. PHAM

Applicant(s)/Patent under
Reexamination

IWAI ET AL.

Art Unit

2618

SEARCHED

Class	Subclass	Date	Examiner
455	575.1	4/12/2006	PHAM
	575.5		
	575.6		
	575.7		
	97		
343	700		
	702	4/12/2006	PHAM

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR